

## Supplementary Information

# Laser patternable graphene field emitters for plasma displays

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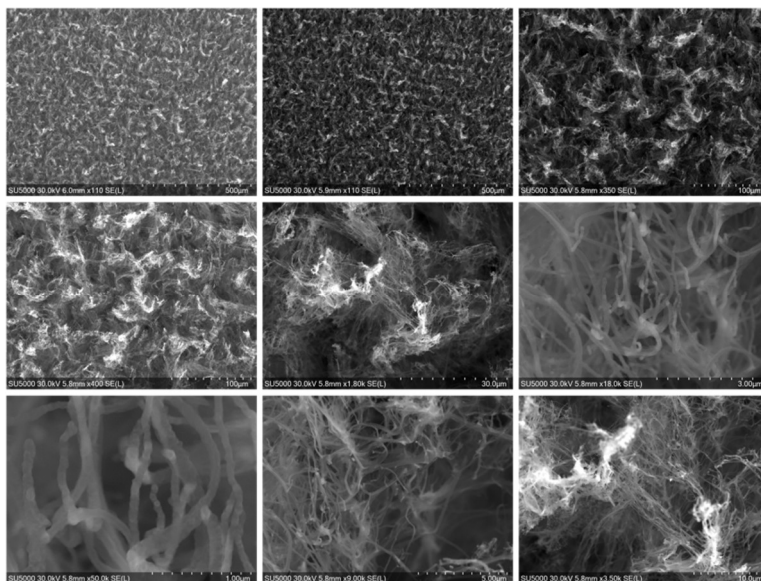
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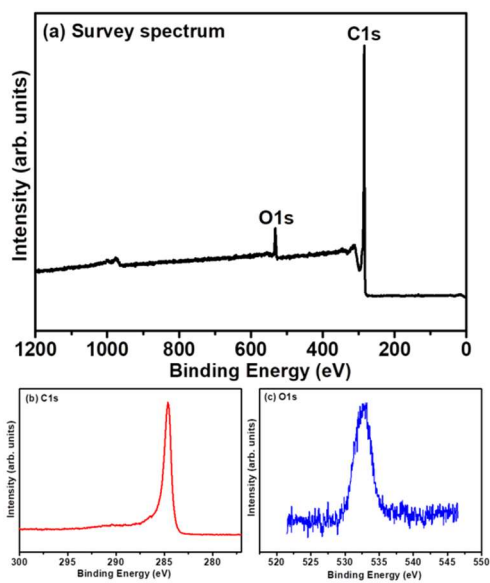
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**Figure S1.** FESEM micrographs of the LIGNs, indicating the homogenous morphology of the nanoribbons in graphene film.



**Figure S2.** (a) The X-ray photoelectron spectroscopic (PHI 6000; Al  $K\alpha$  radiation with an energy of 1486.6 eV and an energy resolution of 0.47 eV) survey spectrum of the LIGNs shows dominant carbon and a small oxygen peaks of 96.3 at.% and 3.7 at.%, respectively. (b) C1s and O1s spectra of the LIGNs.

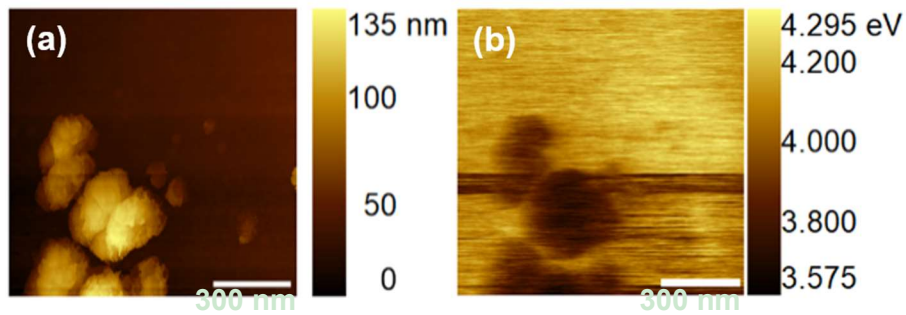
Kelvin Probe Force Microscopy (KPFM) measurements were performed to find the work function of LIGNs using a Park NX-10 Atomic force microscope equipped with PPP-EFM probes (Nanosensors). In KPFM the cantilever is driven in non-contact regime at a frequency slightly larger than the fundamental resonant frequency and an oscillation amplitude set point of 18 nm. An AC bias of 2 V amplitude at a frequency of 17 kHz was applied to the cantilever to probe electrostatic forces. The contact potential difference ( $V_{CPD}$ ) between the conducting AFM tip and the sample is,

$$V_{CPD} = \frac{\varphi_{Tip} - \varphi_{Sample}}{-e} \quad (1)$$

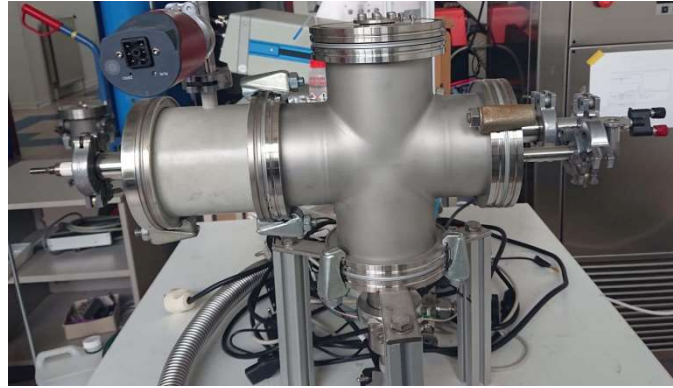
where  $e$  is the electronic charge,  $\varphi_{Tip}$  and  $\varphi_{Sample}$  are the work functions of the AFM tip and the LIGNs film, respectively.

After determining the work function of the AFM tip using a freshly exfoliated highly oriented pyrolytic graphite (HOPG) film of a known work function (4.65 eV) [S1], the work function of the LIGNs was calculated using the relation,

$$\varphi_{LIGNs} = \varphi_{Tip} + eV_{CPD} \quad (2)$$



**Figure S3.** (a) Surface topography and (b) work function map of the LIGNs.



**Figure S4.** Photograph of the homemade PI instrument.

**Table S1.** Comparison between the field electron emission characteristics of LIGNs and other field emitters.

Materials	Turn-on field (V/ $\mu\text{m}$ )	Field enhancement factor	Lifetime (min)
VS <sub>2</sub> nanosheet [S2]	1.4	5588	240
Metallic nanowire-graphene hybrids [S3]	---	3533	0.8
BaO nanostructures [S4]	1.24	2458	---
Carbon-doped ZnO film [S5]	18.0	474	61
Diamond-like carbon films [S6]	40.0	---	---
SiC nanowires [S7]	0.95	4670	360
Multi-walled carbon nanotubes [S8]	4.1	1546	---
Single-walled carbon nanotubes [S9]	2.8	3066	---
Diamond pyramidal microtips [S10]	1.8	4580	210
LIGNs [Present study]	0.44	4578	160

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